

<b>Notice of References Cited</b>	Application/Control No. 10/772,422	Applicant(s)/Patent Under Reexamination KIM ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0051466	05-2002	Bruckman, Leon	370/474
*	B	US-2002/0015422	02-2002	Inada et al.	370/474
	C	US-			
	D	US-			
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**FOREIGN PATENT DOCUMENTS**

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